

IEC QUALITY ASSESSMENT SYSTEM (IECQ)

For rules and details of the IECQ visit www.iecq.org

Schedule of Scope to Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L JQAJP 13.0002

CB Certificate No.: JQAQ0002-001-T

Schedule Number: IECQ-L JQAJP 13.0002-S

Rev No.: 12

Revision Date: 2025/12/26

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TESTD PARTS

Fixed capacitor, Fixed resistor, Semiconductor Integrated Circuit

ENVIRONMENTAL TEST

IEC 60068-2-1:2007

Cold

IEC 60068-2-2:2007

Dry heat

STRESS TEST

JEITA ED-4701/302B:2020

Environmental and endurance test methods for semiconductor devices (Stress test I-2)

Test method 305E

Charged device model electrostatic discharge (CDM/ESD)

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MEASUREMENT RANGE

Passive component

| Type / Part name | Measurable property value | Measuring range |
|------------------|--|--|
| Fixed capacitor | (1)Voltage endurance (DC) | : AC,DC $0 \sim 5kV$ |
| | (2)Insulation resistance | : $5 \times 10^5 \Omega \sim 10^{14} \Omega$ |
| | (3)leakage current | $1 \times 10^{-3} \sim 10 \text{ A}^{-11}$ |
| | (4)Capacitance | : $18pF \sim 1F^*$ |
| | (5)Dielectric loss tangent(D factor) | : 10* min |
| | (6)Impedanc | : $1\Omega \sim 10^* M\Omega$ |
| | Attention: * The mark varies according to measurement frequency. | |
| Fixed resistor | (1)Resistance value | $:1 \Omega \sim 100 M\Omega$ |
| | (2)Insulation resistance | : $5 \times 10^5 \Omega \sim 2 \times 0^{14} \Omega$ |
| | (3)Voltage endurance | : AC,DC $0 \sim 5kV$ |
| CMOS IC | (1)The high-level output voltage | :±30V |
| | (2)The low-level output voltage | :±30V |
| | (3)The high-level input voltage | :±20V |
| | (4)Low-level input electric current | :±20V |
| | (5)High-level output electric current | :±300mA |
| | (6)Low-level output electric current | :±300mA |
| | (7)Static consumption electric current | :±300mA |
| | (8)Input current | :±300mA |

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